

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In Re:	Stefan Schek	Confirmation No:	4430
Application No:	10/501,686	Art Unit:	2182
Filed:	December 29, 2005	Examiner:	Sorrell, Eron J.
For:	Method for Data Processing in a Scan Microscope Comprising a Fast Scanner and Scan Microscope Comprising a Fast Scanner		
Customer No.:	29127		
Attorney Docket No.	21295.87 (E0614US)		

### **AMENDMENT AND RESPONSE AFTER FINAL ACTION**

Mail Stop AF  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

In response to the pending final Office Action, mailed November 20, 2009, (Paper No. 20091109), please amend the above-identified patent application as follows:

Amendments to the Claims are reflected in the listing of claims in the Amendments to the Claims section.

Reconsideration is requested in view of the remarks set forth in Remarks/Arguments section.

A one-month extension is requested for this response.